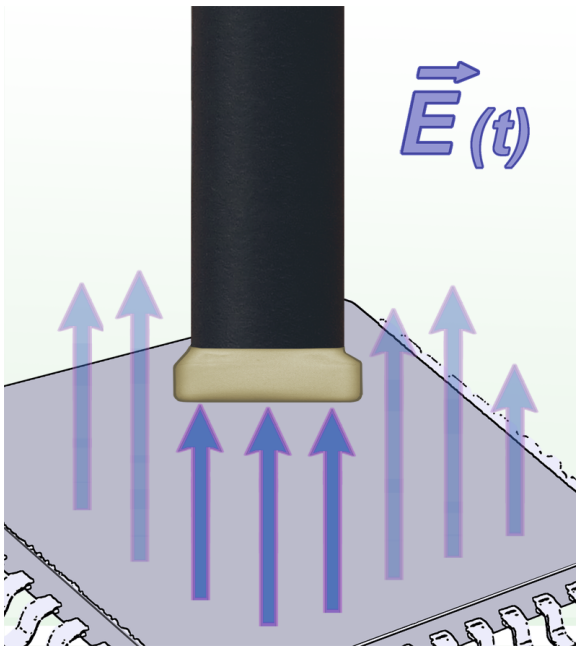


# SX-E 03

E-Field Probe 1 GHz up to 10 GHz



## Short description

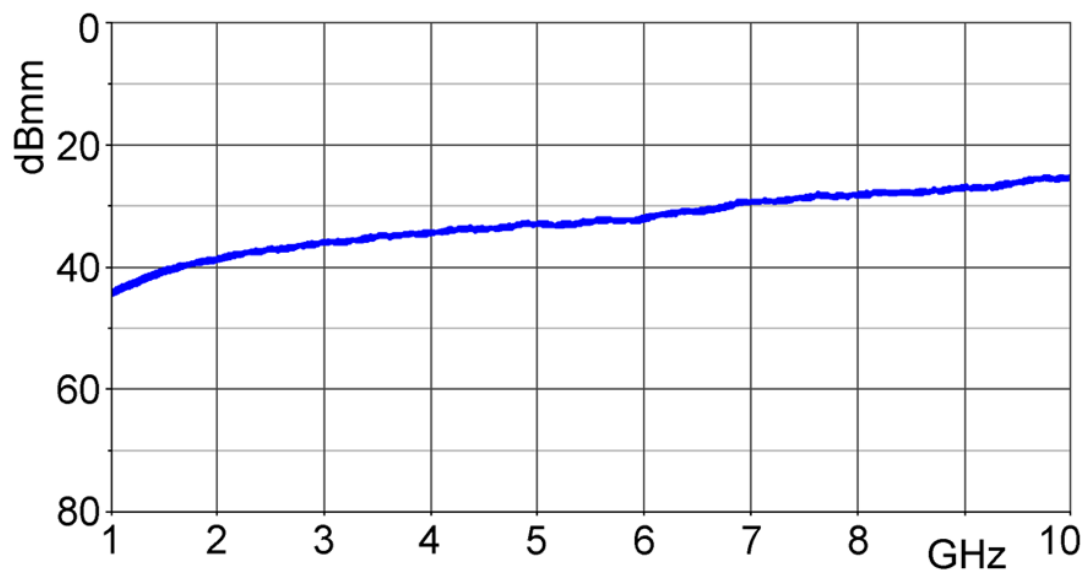
With 4x4 mm dimensions, the electrode on the underside of the probe head of the SX-E 03 is very compact. This allows for the localization of very small E-field sources, e.g. at conducting paths, single components, or on printed circuit boards.

The SX-E 03 is a passive near-field probe. To measure, the probe head is positioned directly onto the measured object, due to higher electrical field strength at the measured object. The near-field probe is small and handy. It has a current attenuating sheath and its upper side is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input.

## Technical parameters

|                        |                           |
|------------------------|---------------------------|
| Frequency range        | 1 GHz ... 10 GHz          |
| Probe head dimensions: | $\approx (4 \times 4)$ mm |
| Connector - output     | SMA, female, jack         |

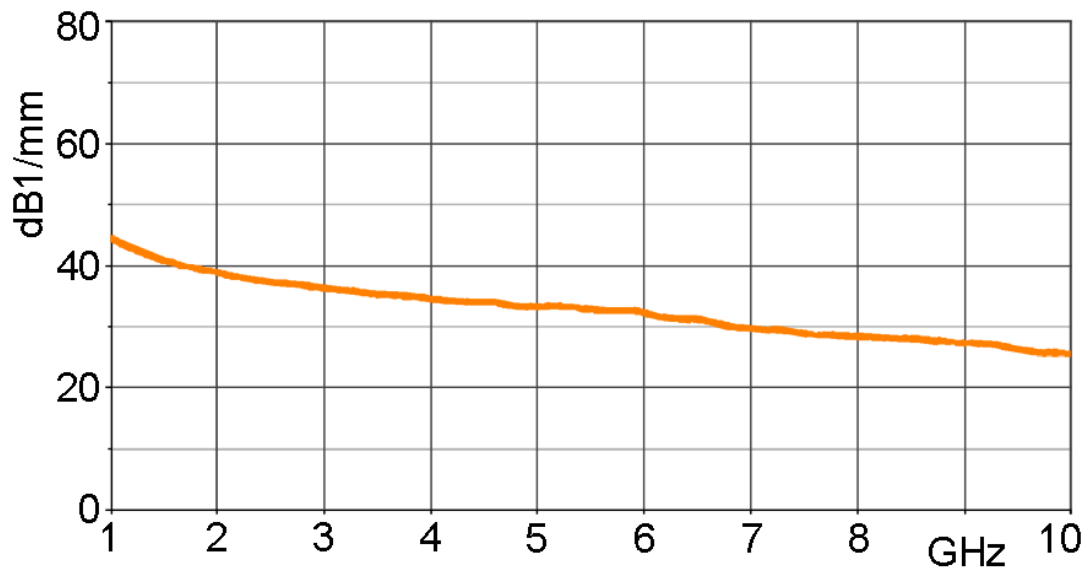
Frequency response [dB $\mu$ V] / [dB $\mu$ V/mm]



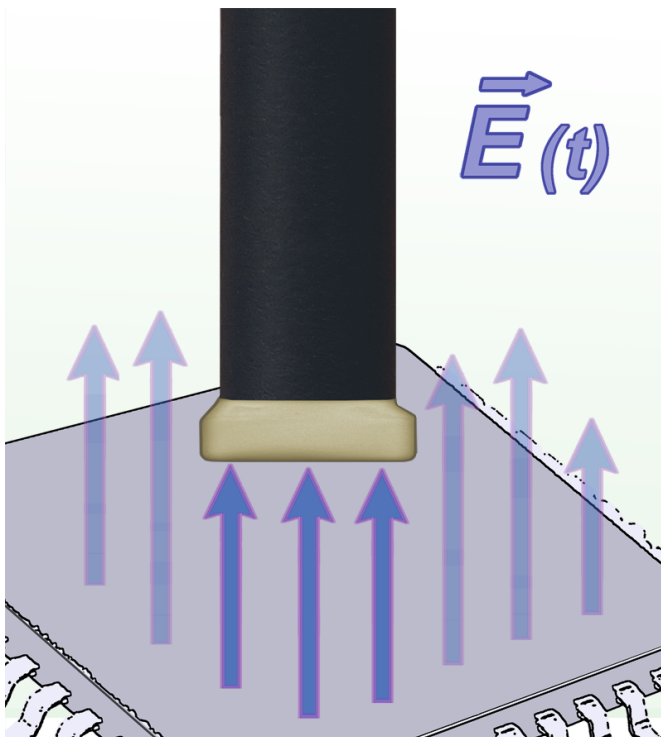
## SX-E 03

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E- field correction curve [dB $\mu$ V/mm] / [dB $\mu$ V]



Measuring principles



# SX-E 03

E-Field Probe 1 GHz up to 10 GHz

**LANGER**  
EMV-Technik

Probe head

